

HiPerFET™ Power MOSFET

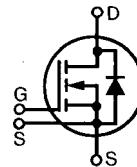
Single MOSFET Die

Preliminary data sheet

IXFN 180N10

V_{DSS} = 100 V
I_{D25} = 180 A
R_{DS(on)} = 8 mΩ

t_{rr} ≤ 250 ns



Symbol Test Conditions

V_{DSS} T_J = 25°C to 150°C
V_{DGR} T_J = 25°C to 150°C, R_{GS} = 1 MΩ

V_{GS} Continuous ±20 V
V_{GSM} Transient ±30 V

I_{D25} T_C = 25°C 180 A
I_{L(RMS)} Terminal (current limit) 100 A
I_{DM} T_C = 25°C; Note 1 720 A
I_{AR} T_C = 25°C 180 A

E_{AR} T_C = 25°C 60 mJ
E_{AS} T_C = 25°C 3 J

dv/dt I_S ≤ I_{DM}, di/dt ≤ 100 A/μs, V_{DD} ≤ V_{DSS} 5 V/ns
T_J ≤ 150°C, R_G = 2 Ω

P_D T_C = 25°C 600 W

T_J -55 ... +150 °C
T_{JM} 150 °C
T_{stg} -55 ... +150 °C

T_L 1.6 mm (0.063 in) from case for 10 s

-55 ... +150 °C

150 °C

-55 ... +150 °C

V_{ISOL} 50/60 Hz, RMS t = 1 min 2500 V~
I_{ISOL} ≤ 1 mA t = 1 s 3000 V~

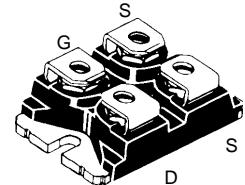
M_d Mounting torque 1.5/13 Nm/lb.in.
Terminal connection torque 1.5/13 Nm/lb.in.

Weight 30 g

Maximum Ratings

miniBLOC, SOT-227 B (IXFN)

E153432



G = Gate
S = Source
D = Drain

Either Source terminal at miniBLOC can be used as Main or Kelvin Source

Features

- International standard package
- Encapsulating epoxy meets UL 94 V-0, flammability classification
- miniBLOC with Aluminium nitride isolation
- Low R_{DS(on)} HDMOS™ process
- Rugged polysilicon gate cell structure
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
- Fast intrinsic Rectifier

Applications

- DC-DC converters
- Synchronous rectification
- Battery chargers
- Switched-mode and resonant-mode power supplies
- DC choppers
- Temperature and lighting controls
- Low voltage relays

Advantages

- Easy to mount
- Space savings
- High power density

Symbol Test Conditions

(T_J = 25°C, unless otherwise specified)

Characteristic Values

	Min.	Typ.	Max.
V_{DSS} V _{GS} = 0 V, I _D = 3 mA	100		V
V_{GS(th)} V _{DS} = V _{GS} , I _D = 8 mA	2		4 V
I_{GS} V _{GS} = ±20 V, V _{GS} = 0 V			±100 nA
I_{DSS} V _{DS} = V _{DSS} V _{GS} = 0 V	T _J = 25°C T _J = 125°C		100 μA 2 mA
R_{DS(on)} V _{GS} = 10 V, I _D = 0.5 • I _{D25}	Note 2		8 mΩ

V_{DSS} V _{GS} = 0 V, I _D = 3 mA	100		V
V_{GS(th)} V _{DS} = V _{GS} , I _D = 8 mA	2		4 V
I_{GS} V _{GS} = ±20 V, V _{GS} = 0 V			±100 nA
I_{DSS} V _{DS} = V _{DSS} V _{GS} = 0 V	T _J = 25°C T _J = 125°C		100 μA 2 mA
R_{DS(on)} V _{GS} = 10 V, I _D = 0.5 • I _{D25}	Note 2		8 mΩ

Symbol Test Conditions
 $(T_J = 25^\circ\text{C}$, unless otherwise specified)

Symbol	Test Conditions	Characteristic Values		
		Min.	Typ.	Max.
I_{fs}	$V_{DS} = 10 \text{ V}; I_D = 60 \text{ A}$, Note 2	60	90	S
C_{iss}		9100		pF
C_{oss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	3200		pF
C_{rss}		1600		pF
$t_{d(on)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$ $R_G = 1 \Omega$ (External),	50		ns
t_r		90		ns
$t_{d(off)}$		140		ns
t_f		65		ns
$Q_{g(on)}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = 0.5 \cdot I_{D25}$	360		nC
Q_{gs}		65		nC
Q_{gd}		190		nC
R_{thJC}	LOC, SOT-227 B		0.21	K/W
R_{thCK}	miniBLOC, SOT-227 B	0.05		K/W

Source-Drain Diode

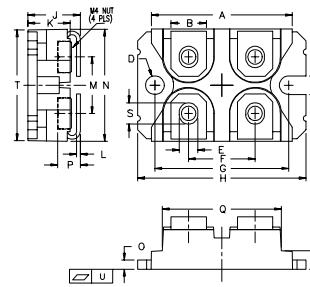
$(T_J = 25^\circ\text{C}$, unless otherwise specified)

Symbol Test Conditions

Symbol	Test Conditions	Characteristic Values		
		Min.	Typ.	Max.
I_s	$V_{GS} = 0$		180	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		720	A
V_{SD}	$I_F = 100 \text{ A}, V_{GS} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = 50 \text{ A}, -di/dt = 100 \text{ A}/\mu\text{s}, V_R = 50 \text{ V}$	1.1	250	ns
		13		μC
				A

- Notes:
1. Pulse width limited by T_{JM} .
 2. Pulse test, $t \leq 300 \text{ ms}$, duty cycle $d \leq 2 \%$

miniBLOC, SOT-227 B



M4 screws (4x) supplied

Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

Figure 1. Output Characteristics at 25°C

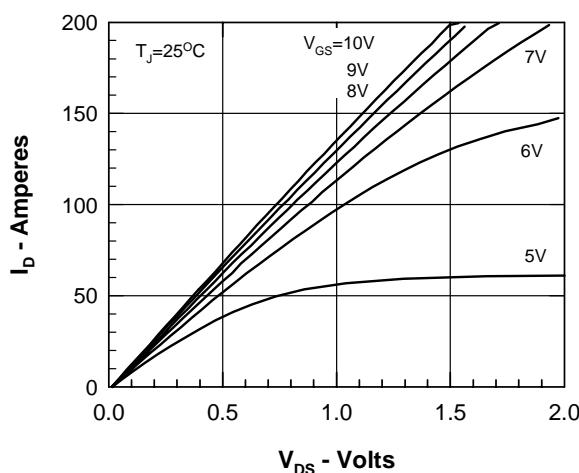
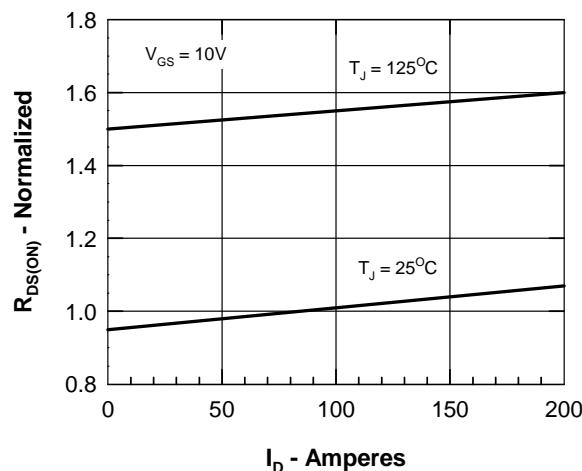
Figure 3. $R_{DS(on)}$ normalized to 15A/25°C vs. I_D 

Figure 5. Drain Current vs. Case Temperature

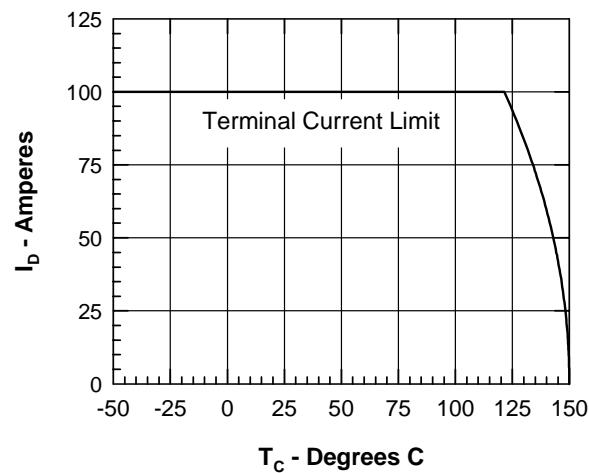


Figure 2. Output Characteristics at 125°C

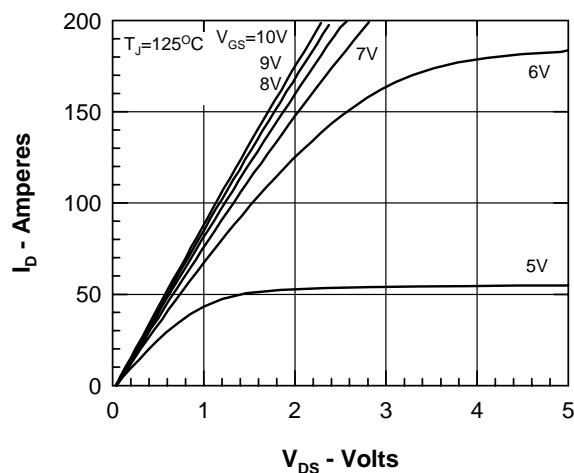
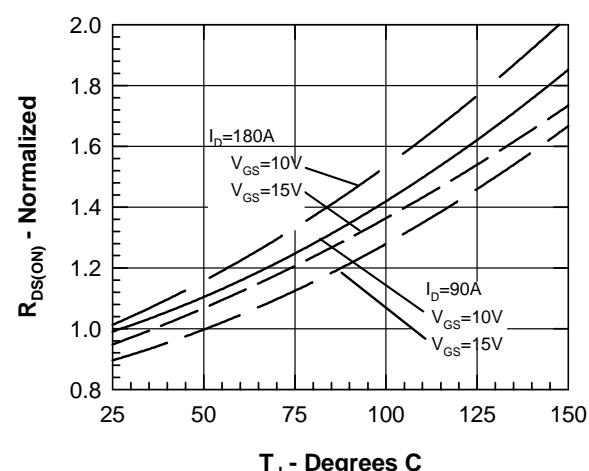
Figure 4. $R_{DS(on)}$ normalized to 15A/25°C vs. T_J 

Figure 6. Admittance Curves

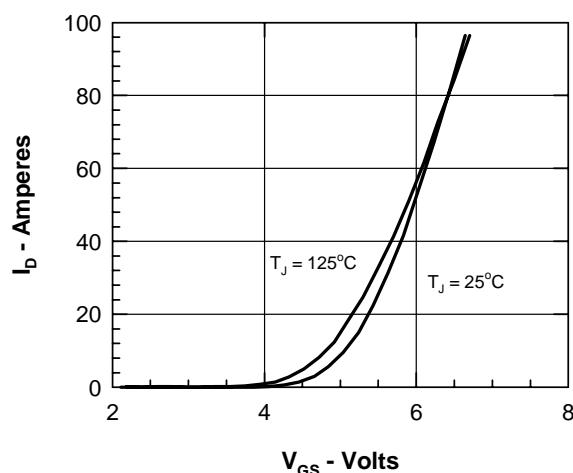


Figure 7. Gate Charge

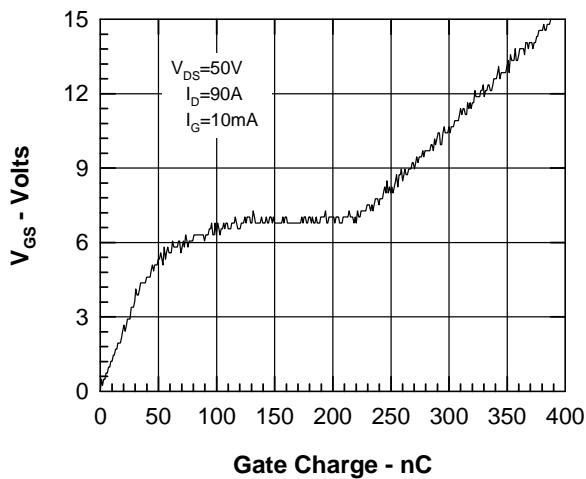


Figure 8. Capacitance Curves

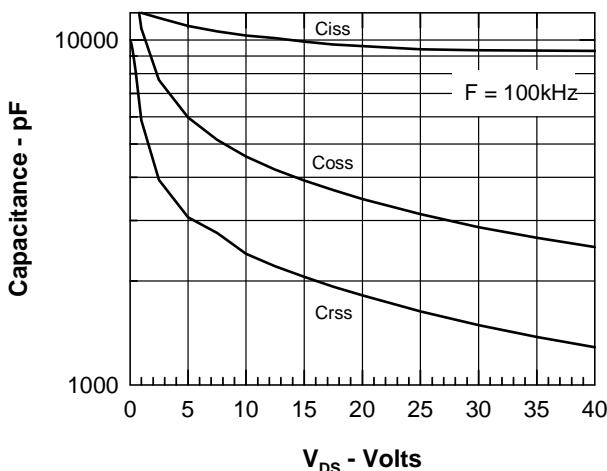


Figure 9. Forward Voltage Drop of the Intrinsic Diode

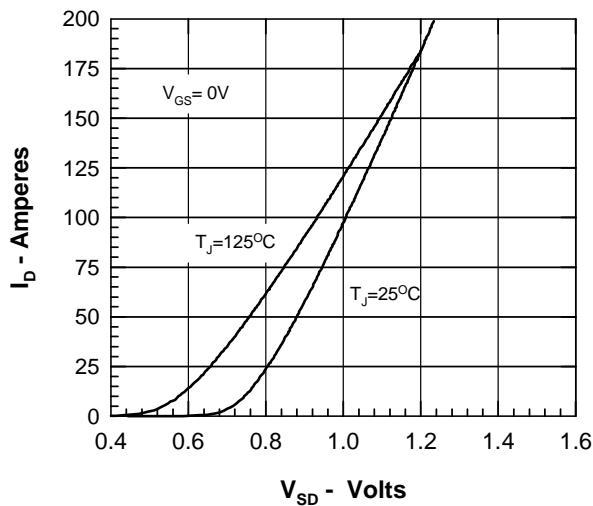


Figure 10. Forward Bias Safe Operating Area

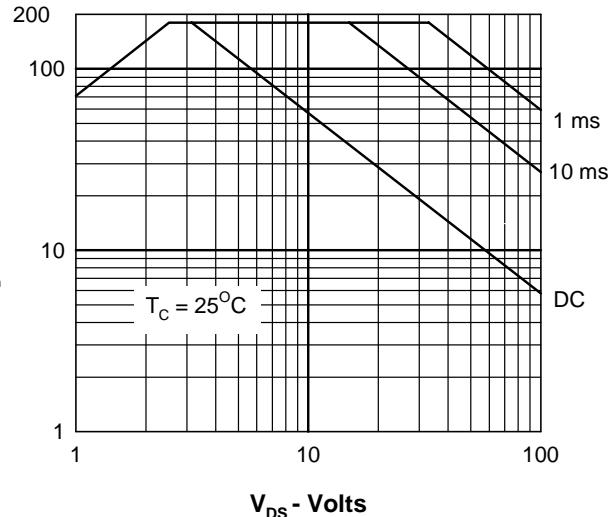


Figure 11. Transient Thermal Resistance

